

High Temperature BSE Detector

Electrode-based sensor technology for in-situ microscopy



Electrode-based detector

To unlock the potential of advanced high-temperature in-situ microscopy, we combined bespoke electronics, mechanics and software for a calibrated 4Q detector.

Calibrated amplification

Two-stage amplification for each of the four electrodes, with independent and calibrated controls for brightness and contrast

make · explore · discover

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Quadrant electrodes

Backscattered electrons are collected using light-blind electron sensors in four-quadrant geometry

Galvanic isolation

Bias voltage is applied to the electrodes to enhance or inhibit detection of low energy electrons

Standard interfaces

Control over USB 2.0 and analog video signals output on RJ45 connectors for modular system integration



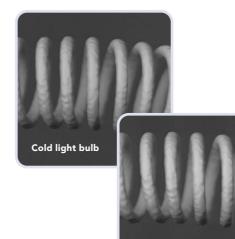
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Motorized insertion

Port-mounted and bellow-sealed with motorized insertion/retraction, high-precision XYZ alignment and touch alarm

Quantitative in-situ experiments

Image and measure surfaces at high-temperatures, in the presence of environmental gasses





- Electronic gains, offsets and bias are
- Amplification is temperature stabilized - Current collected into sensing

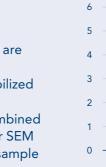
Hot light bulb

electrodes is measured when combined with calibrated scan controller for SEM (DISS6) and COMPO calibration sample

Quantitative

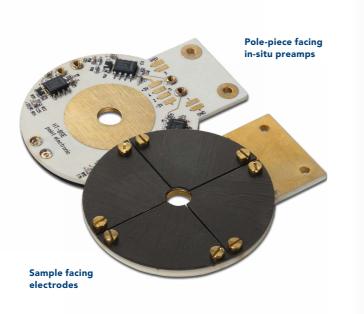
factory calibrated

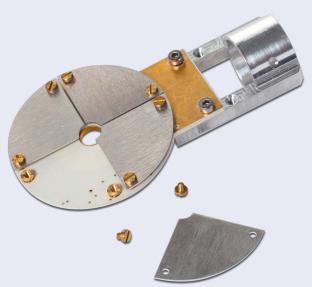
measurements



Quadrant electrodes

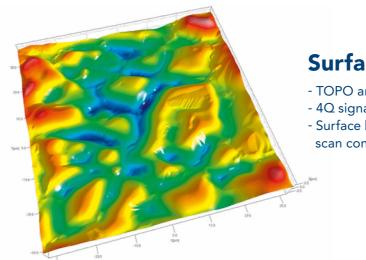
- Four metal electrodes with carbon coating
- Each electrode with own in-situ preamplifier
- Adjustable bias voltage applied to all
- Size and geometry adapted to SEM model





Easy to clean

- Entire detector front end is easily removed
- Electrodes can be cleaned and recoated as needed
- Screws are used for easy on-site dissassembly
- Various electrode coatings may be reapplied



High temperatures

- Electrodes are blind to light emitted by hot samples - Thermal electrons are filtered using the detector bias - Maximum temperature limited only by radiative heating - Compatible with laser heating



Surface analysis

- TOPO and COMPO mix is done in the detector hardware - 4Q signals are designed for topographic reconstruction - Surface height/topography is measured when combined with scan controller for SEM (DISS6) and TOPO calibration sample

Hardware

| Sensors | 4x quadrant electrodes |
|-------------------------|--|
| | Carbon coated |
| | typ. 5 mm inner diameter |
| | typ. 25 mm outer diameter |
| | -1010 V voltage bias |
| Preamplifiers | 4x mounted in-situ |
| | Galvanic isolation |
| | 5x10 ⁷ V/A |
| | 50 kHz bandwidth |
| Main amplifier (MICS-4) | 4x independent signal channels |
| | -1.25 1.25 V (-5050 mV with attenuator) input offset |
| | 1× 1,800× gain |
| | -1.25 1.25 V output offset |
| | 3.4 MHz34 Hz low-pass filter |
| | Automated 4Q global brightness and contrast |
| | Automated input offsets (dark correction) |
| | Automated gain normalization (bright correction) |
| | COMPO hardware mix signal (sum of BSE1BSE4) |
| | TOPO hardware mixed signal (mix of BSE1BSE4) |
| Mechanics (LIMA) | Port mounted, with vacuum bellows |
| | Motorized insertion/retraction motion |
| | -44 mm manual lateral and height alignment |
| | 10 µm repositioning step size |
| | Integrated touch alarm, with automatic stop and retraction |
| | Passive cooling |
| Interfaces | 1x USB 2.0 for amplifier control |
| | 1x USB 2.0 for motion control |
| | 1x RJ45 signal outputs |
| Signal outputs | Independent BSE1BSE4 |
| | COMPO (sum of BSE1BSE4) |
| | TOPO (mix of BSE1BSE4) |
| | |

Software

| Control | Detector drawing with selectable quadrants | |
|--------------------|---|--|
| | Bias, brightness and contrast controls | |
| | Individual quadrants, or grouped COMPO/TOPO control | |
| | Automatic go to inserted/retracted positions | |
| | Fine repositioning/adjustments in mm units | |
| In-situ automation | XML file format open/save settings | |
| | JSON/RPC interface for remote control | |
| | Automated brightness and contrast | |
| Operating system | Windows 11 Windows 7 | |
| | | |

PC/Laptop, display (optional)

| PC/Laptop | Intel Core i3 minimum | |
|------------------|---|--|
| | 2 × USB 2.0 minimum | |
| Display | $1,280 \times 1,024$ resolution minimum | |
| | 1 × display recommended | |
| Operating system | n Windows 11 Windows 7 | |
| | Network connection recommended for remote support | |
| | | |

| Parts and cables | |
|---------------------|-------------|
| HT BSE detector | Standard 1× |
| Flange adaptor | Standard 1x |
| Power adaptor | Standard 1x |
| Signal cable | Standard 1× |
| USB control cables | Standard 2x |
| USB flash drive | Standard 1× |
| PC, keyboard, mouse | Optional 1× |
| Displays | Optional 1× |
| | |

Software packages

| Drivers | PEUSB |
|-----------|--------------------------|
| Libraries | MICSControl, LIMAControl |
| Software | Detector control app |
| | |

| typ. 50 x 16 x 16 cm, typ 5.5 kg |
|----------------------------------|
| typ. Ø40 mm, h: 5 mm |
| depending on instrument |
| typ. 11 x 3 x 5 cm, typ 0.5 kg |
| typ. 36 x 32 x 60 cm, typ 7 kg |
| |

| Site requirements | | |
|-------------------|------------|----------|
| | Power | 1× main |
| | | On the s |
| | Microscope | 1× to 4× |
| | | Free BS |
| | Space | Detecto |



ins 108..253 VAC single phase 50/60 Hz

same earth as the microscope

x video signal inputs on the SEM electronics

SE port on the SEM chamber

or power adaptor may be placed on the floor

Our design principles

We look back on 30 years of experience in development and manufacture of high-performance instruments and technologies for microscopy.

We are driven by an ambition to expand abilities and to improve performance of electron microscopes.

Our aspiration is to make the best quality tools and to join our customers on their journeys of scientific exploration and discovery.

Performance

- Microscopy must be a reliable and enjoyable experience
- Design for highest speed and resolution at the lowest noise
- Develop smart independent controllers for live optimization
- Support new users with simple and automated controls
- Assist advanced users with access to all parameters

Efficiency

- Microscopes must provide an uninterrupted focus
- Use standard microscope controls and data formats
- Give instant feedback with live image mixing and processing
- Add bespoke software tools and algorithms for repetitive tasks
- Enable more developers with libraries and documentation

Environment

- Products and technologies must be sustainable
- Reduce power consumption through smart design
- Minimize material use, embrace reuse where possible
- Save weight and volume for shipping and maintenance
- Enable everyone to develop sustainable innovations

Quantification

- Data and control must be in physical units
- Calibrate, in production, for measured inputs and outputs
- Provide samples, procedures and software for calibration
- Give all control parameters in device independent values
- Ensure safe operation according to IEC61010-1 and IEC 61326-1

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